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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (Rev. 7-80) PATENT AND TRADEMARK OFFICE **LIST OF PRIOR ART CITED BY APPLICANT** (Use several sheets if necessary)	ATTORNEY DOCKET NO. 14131.0004U2	SERIAL NO. 09/960,218 CONFIRMATION NO. 5873
	APPLICANT: Crabtree et al.	
	FILING DATE: September 21, 2001	GROUP: 2613

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
gh	A1	6,185,314	02/06/01	Crabtree et al.			
gl	A2	5,097,328	03/17/92	Boyette			

FOREIGN PATENT DOCUMENTS

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

94	A3	Burt et al. Object Tracking with a Moving Camera. *Proceedings Workshop on Visual Motion, Irvine, California* (1989)
94	A4	Cai et al. Automatic Tracking of Human Motion in Indoor Scenes Across Multiple Synchronized Video Streams. Pgs. 356-362 (Abstract - Department of Electrical and Computer Engineering, The University of Texas at Austin) (1990)
94	A5	Celenk et al. Moving Object Tracking Using Local Windows. *Proceedings IEEE International Symposium on Intelligent Control.* Pgs. 180-185 (1988)
94	A6	Liao et al. Tracking Human Movements Using Finite Element Methods. Pgs. 1-11 (Paper - Dept. of Electrical and Computer Engineering, The University of Texas at Austin) (1994)
94	A7	Montera et al. Object Tracking Through Adaptive Correlation. *Optical Engineering* 33(1):294-302 (1994)
94	A8	Salari et al. Feature Point Correspondence in the Presence of Occlusion. *Pattern Analysis and Machine Intelligence* 12(1):87-91 (1990)
94	A9	Sethi et al. Finding Trajectories of Feature Points in a Monocular Image Sequence. *Pattern Analysis and Machine Intelligence* PAMI-9(1):56-73 (1987)
94	A10	Tsai et al. Uniqueness and Estimation of Three-Dimensional Motion Parameters of Rigid Objects with Curved Surfaces. *IEEE.* Pgs. 112-118 (1982)
94	A11	Tsai et al. Estimating Three-Dimensional Motion Parameters of a Rigid Planar Patch. *IEEE.* Pgs. 94-97 (1981)

EXAMINER: *[signature]*   DATE CONSIDERED: 6/22/2004

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.